## Notice of R ferenc s Cit d

Application/Control No	Applicant(s)/Pa Reexamination SHIDA ET AL.	Applicant(s)/Patent Under Reexamination SHIDA ET AL.		
Examiner	Art Unit			
Nikolas J. Uhlir	1773	Page 1 of 1		

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6303217	10-2001	Malhotra et al.	428/332
	В	US-6150015	11-2000	Bertero et al.	428/332
	С	US-5789056	08-1998	Bian et al.	428/332
	D	US-5583727	12-1996	Parkin et al.	360/113
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	IEEE Transactions on Magnetics, Vol 28, #5, Sept. 1992, Paik et al. pp 3084-3086
	V	IEEE Transactions on Magnetics, Vol. 27, #6, Nov. 1991, Tani et al. pp 4736-4733
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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